

A Bibliography of electron diffraction applications indexed by material.

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Introduction:

This article contains an alphabetical list of many of the materials which have been studied by electron diffraction, CBED and precession electron diffraction, with references to the original papers. The list is intended to prevent repetition of past work, to summarise the knowledge that has been obtained by electron diffraction, and to assist with the indexing of patterns of these materials in future work. Only papers which were listed through following search have been included:

- 1) name a material by chemical formula in the title together with keywords of CBED or electron diffraction;
- 2) name a material by chemical formula together with keywords of CBED or electron diffraction in google scholar and webofknowledge.

Thus many papers on, for example "CBED of quasicrystals", or "CBED of oxide superconductors" etc. are not listed. Since systematic naming conventions are not always used (YBa₂Cu₃O₇, for example, should actually be written Ba₂YCu₃O₇, etc) it may be necessary to search under several entries. We have simplified many formulae (e.g. by deleting dopants, numbers etc.) for the purposes of alphabetisation.

The list is seen to reflect strongly the interests of the the aircraft industry and the semiconductor industry, together with work on the new oxides.

The original list was published in the book of "Electron microdiffraction" by J.C.H. Spence and J.M. Zuo in 1992. This updated list now includes publications from 1992 to 2016.

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